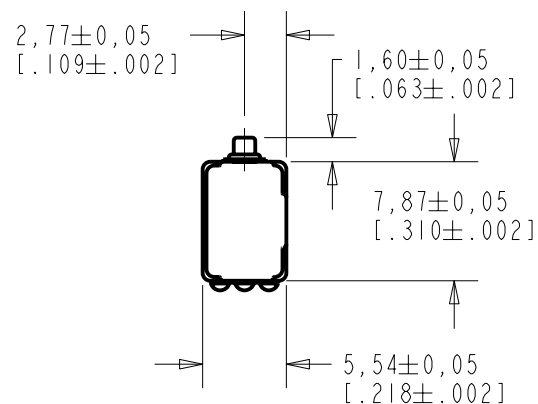


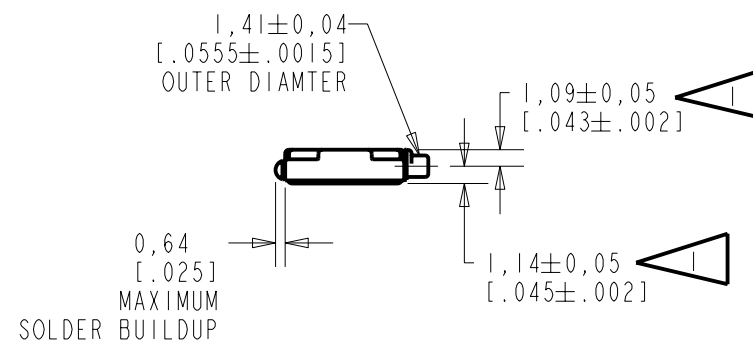
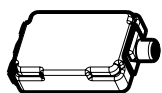
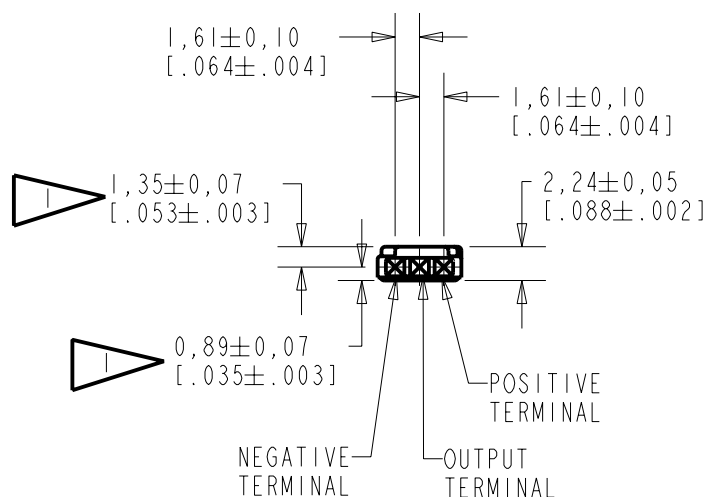
BT-21835-000

SHT 1.1



NOTE:

LOCATED FROM TWO SURFACES FOR CUSTOMER CONVENIENCE. ONLY APPLICABLE FROM ONE SURFACE, NOT TO BE USED TOGETHER. HORIZONTAL LOCATION FOR TERMINAL CENTERED TO $\pm 0,17$ [$.007$].



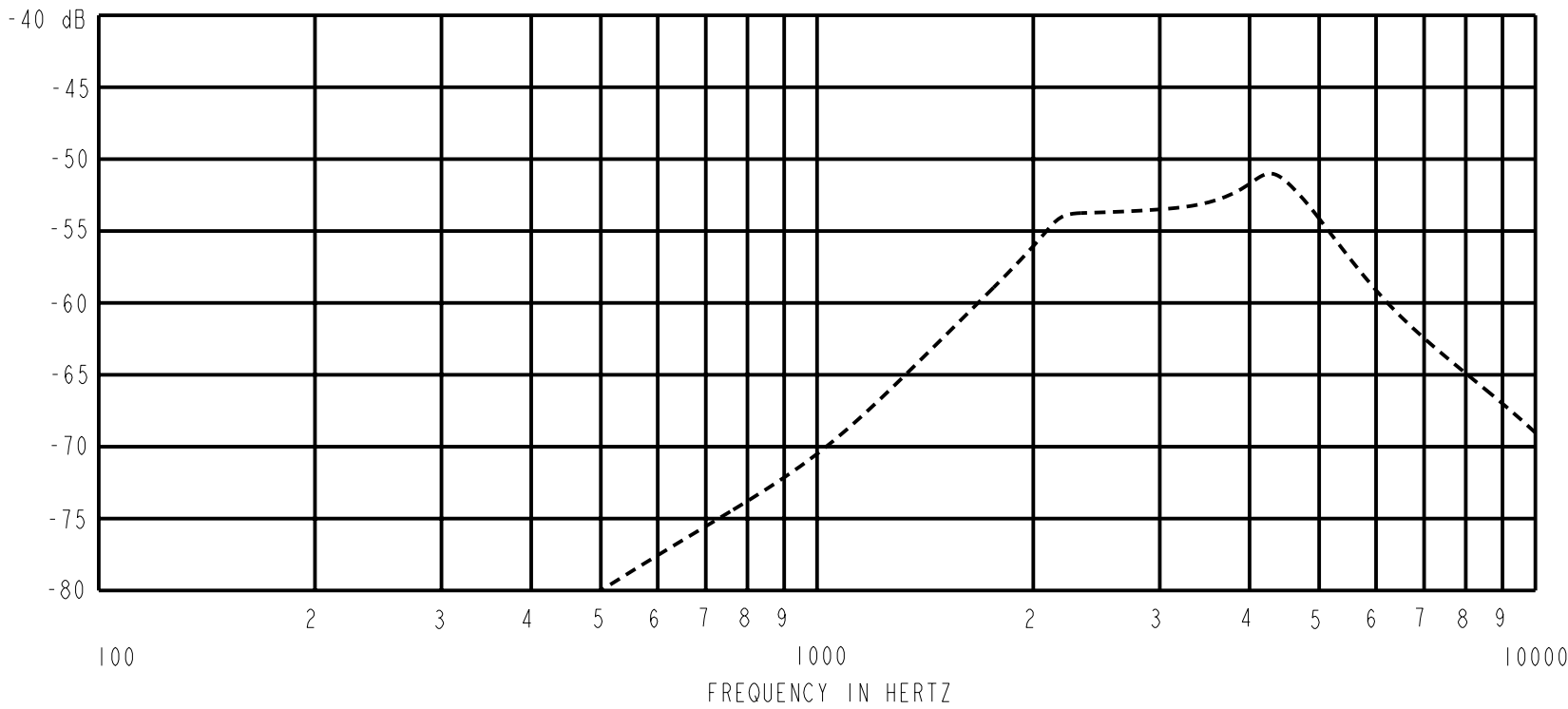
DIMENSIONS IN MILLIMETERS [INCHES]

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Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
			Released	A
A	MI0101318	11-22-06		

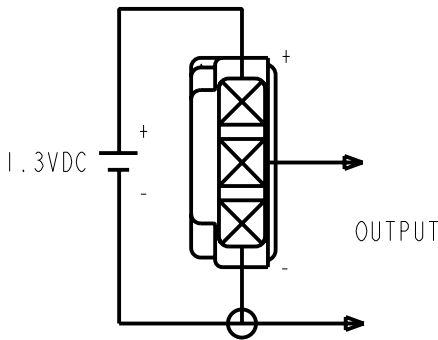
SCALE: 2:1		DR. BY	DATE
DO NOT SCALE DRAWING		LSY	11-22-06
		CK. BY	DATE
TITLE: MICROPHONE		GJP	11-30-06
BT-21835-000		APP. BY	DATE
OUTLINE DRAWING		GJP	11-30-06
SHT 1.1			

SENSITIVITY IN dB RELATIVE TO 1.0 VOLT/0.1 Pa (N/M²)
FOR CONDITIONS SHOWN BELOW.



FREQUENCY	SENSITIVITY		
	MIN.	NOM.	MAX.
1000	---	-70.5	---
3000	-56.5	-53.5	-50.5
≈ 4300	---	-51.0	---

DEVICE CONFORMITY	
RANGE OF DEVIATION FROM 1KHz	
---	-12.0
0	0
-1.5	+6.5



NOTES:

- CASE CONNECTED TO NEGATIVE TERMINAL.
- MICROPHONE TO BE FUNCTIONAL WITH 10 VDC SUPPLY.
- CONFORMS TO REQUIREMENTS SHOWN ON 'ELECTRET MICROPHONE ENVIRONMENTAL QUALIFICATION TEST, SHEET 2.2'.

PORT LOCATION	DC SUPPLY	AMPLIFIER CURRENT DRAIN	SENSITIVITY CHANGE ON REDUCING SUPPLY TO 0.9VDC	"A" WEIGHTED NOISE (RE 1.0 VOLT)	OUTPUT IMPEDANCE OHMS			CAPACITANCE ±50%	
					MIN.	NOM.	MAX.	1-2	1-3
12S	1.3V	50 µA MAX.	3 dB MAX.	-101 dB MAX.	2000	3500	6000	NA	NA

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			Released		A
A	M10101318	11-22-06			
WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION			DR. BY		DATE
			LSY		11-22-06
TITLE: MICROPHONE			CK. BY		DATE
			GJP		11-30-06
PERFORMANCE SPECIFICATION			APP. BY		DATE
			GJP		11-30-06
			BT-21835-000		
			SHT 2.1		

WHEN THESE TESTS ARE USED TO ESTABLISH PRODUCT QUALIFICATION, CORRELATION OF TEST EQUIPMENT WITH KNOWLES ELECTRONICS IS ALSO REQUIRED TO ELIMINATE EQUIPMENT AND TEST METHOD VARIATION.

BECAUSE THIS IS AN ACCELERATED LIFE TEST, IT FOLLOWS THAT THE UNITS WHICH HAVE BEEN TESTED WILL NOT QUALIFY AS IN-WARRANTY RETURNS. SINCE THESE TESTS ARE DESTRUCTIVE IN NATURE, DEVICES SUBJECTED TO THESE TESTS SHOULD NOT BE USED IN PRODUCTION.

I. ACCELERATED DAMP HEAT TEST.

- I.1 PRECONDITIONING:
TIME - 16 HOURS
TEMPERATURE - 22°C ±1°C
HUMIDITY - 60% MAX. R.H.
- I.2 TEST CONDITIONS:
TIME AT CONDITIONS: - 1000 HOURS
TEMPERATURE - 63°C ±1°C
HUMIDITY - 95% R.H. ±2%
VOLTAGE STRESS - DETAILED FIG. 1

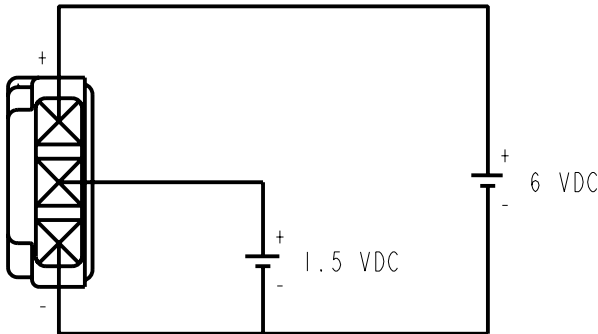


FIG. 1
(AVOID CONDENSATION FALLING ON UNITS UNDER TEST.)

- I.3 INITIAL MEASUREMENTS:
AFTER PRECONDITIONING, MEASURE SENSITIVITY PER SHEET 2.1 OF THE APPLICABLE KNOWLES ELECTRONICS MICROPHONE PERFORMANCE SPECIFICATION.
- I.4 TEST PROCEDURE:
INSERT UNIT(S) INTO TEST CHAMBER PER CONDITIONS OF 1.2.
- I.5 RECOVERY:
TIME - 2 HOURS
TEMPERATURE - 22°C ± 1°C
HUMIDITY - 60% MAX. R.H.
- I.6 FINAL MEASUREMENTS:
MEASURE SENSITIVITY PER CONDITIONS DESCRIBED ON SHEET 2.1.
- I.7 REQUIREMENT:
NO UNITS WILL BE INOPERATIVE FOLLOWING THE TEST AND RECOVERY CYCLE.
2. SHOCK TEST
- 2.1 PRECONDITIONING:
TIME - 16 HOURS
TEMPERATURE - 22°C ± 1°C
HUMIDITY - 60% MAX. R.H.
- 2.2 TEST CONDITIONS:
HALF-SINE IMPULSE DURATION - 100 MICROSECONDS
PEAK AMPLITUDE - 20,000 g
- SPURIOUS DEVIATIONS IN THE HALF-SINE IMPULSE CURVE SHALL BE REDUCED TO WHERE RESULTS ARE NOT APPRECIABLY AFFECTS.
- UNIT(S) TO BE SUBJECTED TO THE TEST CONDITIONS EITHER IN THE COVER UP OR COVER DOWN ORIENTATION.
- 2.3 INITIAL MEASUREMENTS:
AFTER PRECONDITIONING, MEASURE AND RECORD THE 1 kHz SENSITIVITY PER SHEET 2.1 OF THE APPLICABLE KNOWLES ELECTRONICS MICROPHONE PERFORMANCE SPECIFICATION.
- 2.4 TEST PROCEDURE:
STRESS UNIT(S) ACCORDING TO THE ABOVE 2.2 TEST CONDITIONS.
- 2.5 RECOVERY:
UNITS TO BE MEASURED IMMEDIATELY AFTER TEST CYCLE.
- 2.6 FINAL MEASUREMENTS:
MEASURE AND RECORD THE 1 kHz SENSITIVITY PER SHEET 2.1.
- 2.7 REQUIREMENT:
THE UNIT(S) SHALL SHOW A MAXIMUM CHANGE IN 1kHz SENSITIVITY (INITIAL TO FINAL) OF 1.0 dB AS A RESULT OF THE TEST CYCLE.

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WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION			DR. BY	DATE
			LSY	11-22-06
			CK. BY	DATE
			GJP	11-30-06
TITLE: MICROPHONE PERFORMANCE SPECIFICATION			BT-21835-000	
			SHT 2.2	
			APP. BY	DATE
			GJP	11-30-06



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Электрон
Связь**

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С нами вы становитесь еще успешнее!

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